

Peripheral Inspection System And Method**ABSTRACT OF THE INVENTION**

A method of inspecting two or more sides of an object is provided. The method includes generating one set of image data of two or more sides of the object, such as by using spherical mirror segments that project all sides of the object onto a single image and generating an X by Y array of image data of the single image. The projection of the image data is then compensated for, such as by identifying inspection processes to locate defects of the object in the projected image data or by converting the image data from the projected inspection coordinates to Cartesian coordinates. Predetermined inspection processes are then performed on the compensated image data, such as by using the inspection processes that are optimised for use with the projected image data or by converting the projected image data into a Cartesian format and using Cartesian image data inspection processes.

FIG. 1